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PERFORMANCE CHECKSHEET

Model: AVR-EB2A-B
Type: Semiconductor Device Tester
S.N.: 13513
Date: February 8, 2017

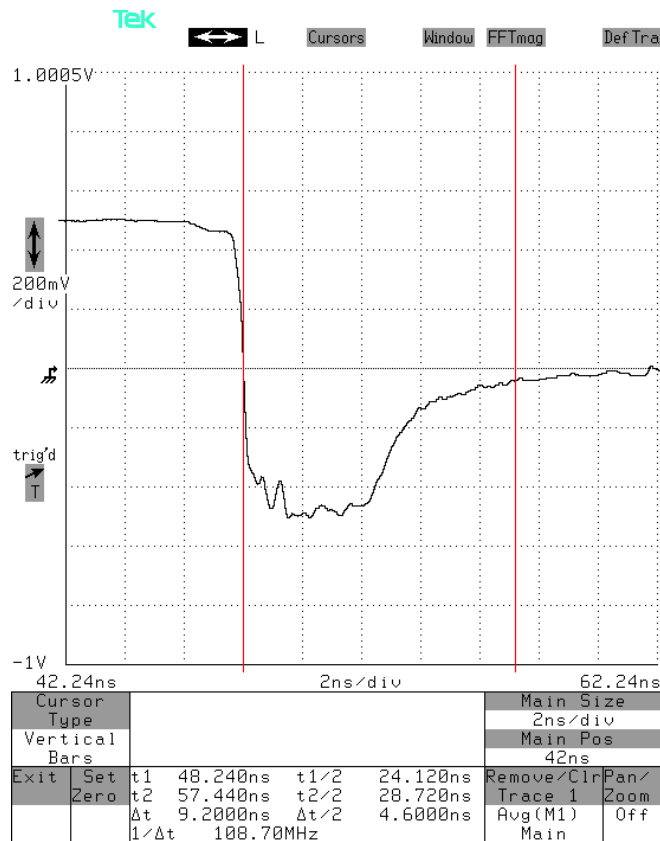
Output Amplitude: to +100 mA, -100 mA
Pulse Width (FWHM): 200 ns
Switching Time,
+ to -, 10%-90%: ≤ 300 ps (at mainframe)
PRF: 1 - 10 kHz
Jitter, Stability: OK
Prime Power: 100-240V AC, 50-60 Hz.

Basic specifications: →

Test Waveforms

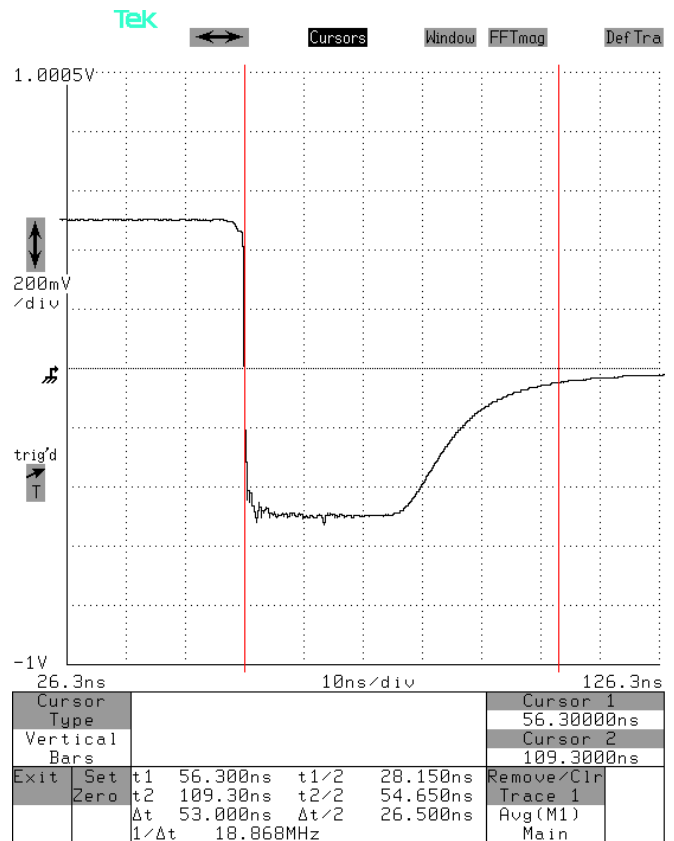
With a 1N4148 installed in the AVX-CA-AR1 test jig, 40 mA/div, 2 ns/div:

With a 1N5811US installed in the AVX-CA-AR1 test jig, 40 mA/div, 10 ns/div:



I_F = +100 mA, I_R = - 100 mA

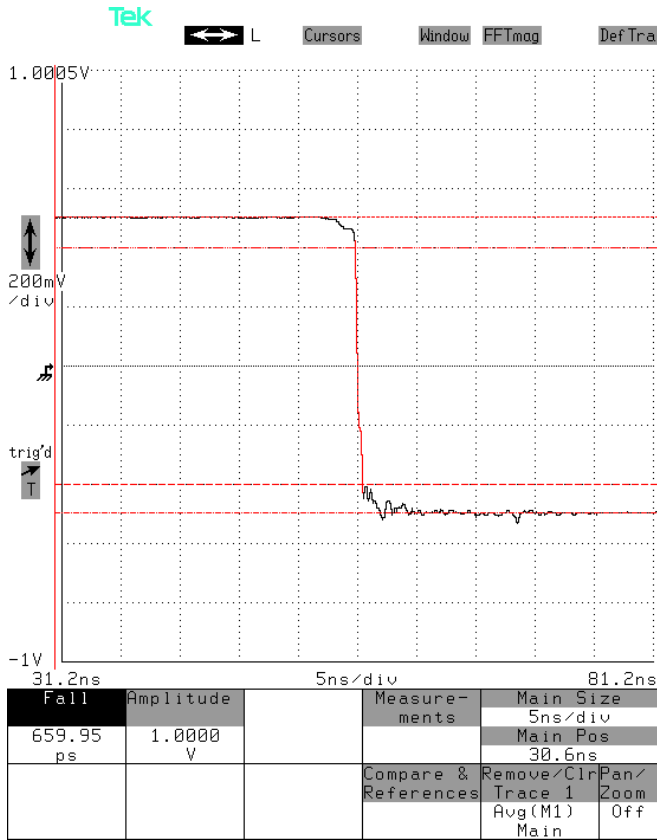
Measured t_{RR} = 9.2 ns.



I_F = +100 mA, I_R = - 100 mA

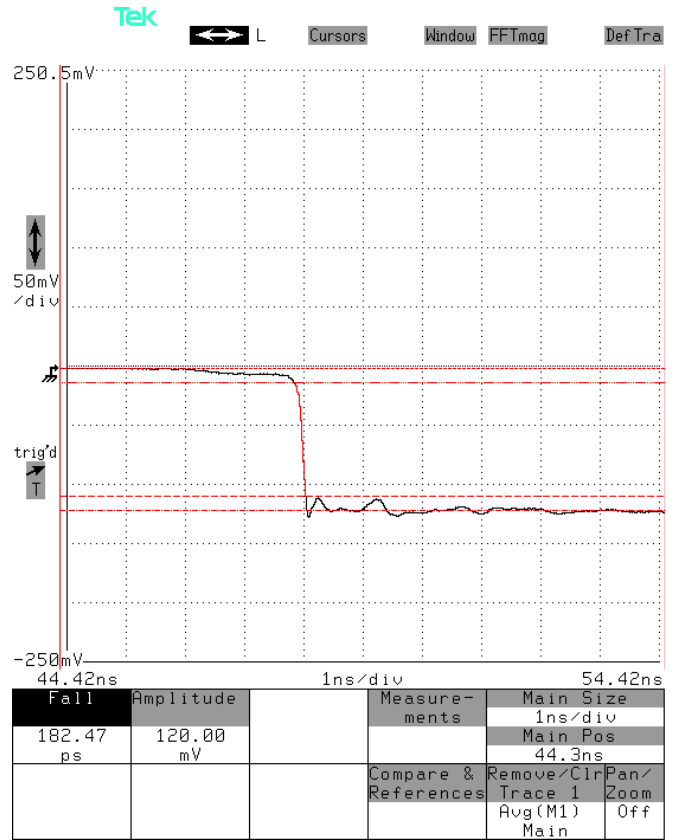
Measured t_{RR} = 53 ns.

Same as previous, scaled to showing switching time, 1N5811US installed in the AVX-CA-AR1 test jig, 40 mA/div, 5 ns/div:



Shows a 10%-90% transition time of < 700 ps.

-24V pulse output directly from mainframe, with the test jig bypassed (5 V/div, 1 ns/div):



Shows a 10%-90% transition time of < 200 ps.